3.3-V PHASE-LOCK LOOP CLOCK DRIVER WITH POWER DOWN MODE

Check for Samples: CDCVF2509A

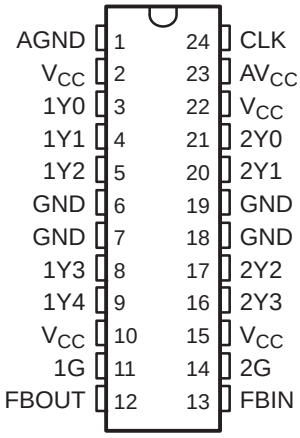
FEATURES

- Designed to Meet and Exceed PC133 SDRAM Registered DIMM Specification Rev. 1.1
- Spread Spectrum Clock Compatible
- Operating Frequency 20 MHz to 175 MHz
- Static Phase Error Distribution at 66 MHz to 166 MHz Is ±125 ps
- Jitter (cyc - cyc) at 60 MHz to 175 MHz Is Typ = 65 ps
- Advanced Deep Submicron Process Results in More Than 40% Lower Power Consumption Versus Current Generation PC133 Devices
- Auto Frequency Detection to Disable Device (Power-Down Mode)
- Available in Plastic 24-Pin TSSOP
- Phase-Lock Loop Clock Distribution for Synchronous DRAM Applications
- Distributes One Clock Input to One Bank of Five and One Bank of Four Outputs
- Separate Output Enable for Each Output Bank
- External Feedback (FBIN) Terminal Is Used to Synchronize the Outputs to the Clock Input
- 25-Ω On-Chip Series Damping Resistors
- No External RC Network Required
- Operates at 3.3 V

APPLICATIONS

- DRAM Applications
- PLL Based Clock Distributors
- Non-PLL Clock Buffer

PW PACKAGE
(TOP VIEW)



DESCRIPTION

The CDCVF2509A is a high-performance, low-skew, low-jitter, phase-lock loop (PLL) clock driver. It uses a PLL to precisely align, in both frequency and phase, the feedback (FBOUT) output to the clock (CLK) input signal. It is specifically designed for use with synchronous DRAMs. The CDCVF2509A operates at a 3.3-V V_{CC}. It also provides integrated series-damping resistors that make it ideal for driving point-to-point loads.

One bank of five outputs and one bank of four outputs provide nine low-skew, low-jitter copies of CLK. Output signal duty cycles are adjusted to 50%, independent of the duty cycle at CLK. Each bank of outputs is enabled or disabled separately via the control (1G and 2G) inputs. When the G inputs are high, the outputs switch in phase and frequency with CLK; when the G inputs are low, the outputs are disabled to the logic-low state. The device automatically goes into power-down mode when no input signal (< 1 MHz) is applied to CLK; the outputs go into a low state.

Unlike many products containing PLLs, the CDCVF2509A does not require external RC networks. The loop filter for the PLL is included on-chip, minimizing component count, board space, and cost.

These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

DESCRIPTION CONTINUED

For application information, see application reports *High Speed Distribution Design Techniques for CDC509/516/2509/2510/2516* (SLMA003) and *Using CDC2509A/2510A PLL with Spread Spectrum Clocking (SSC)* (SCAA039).

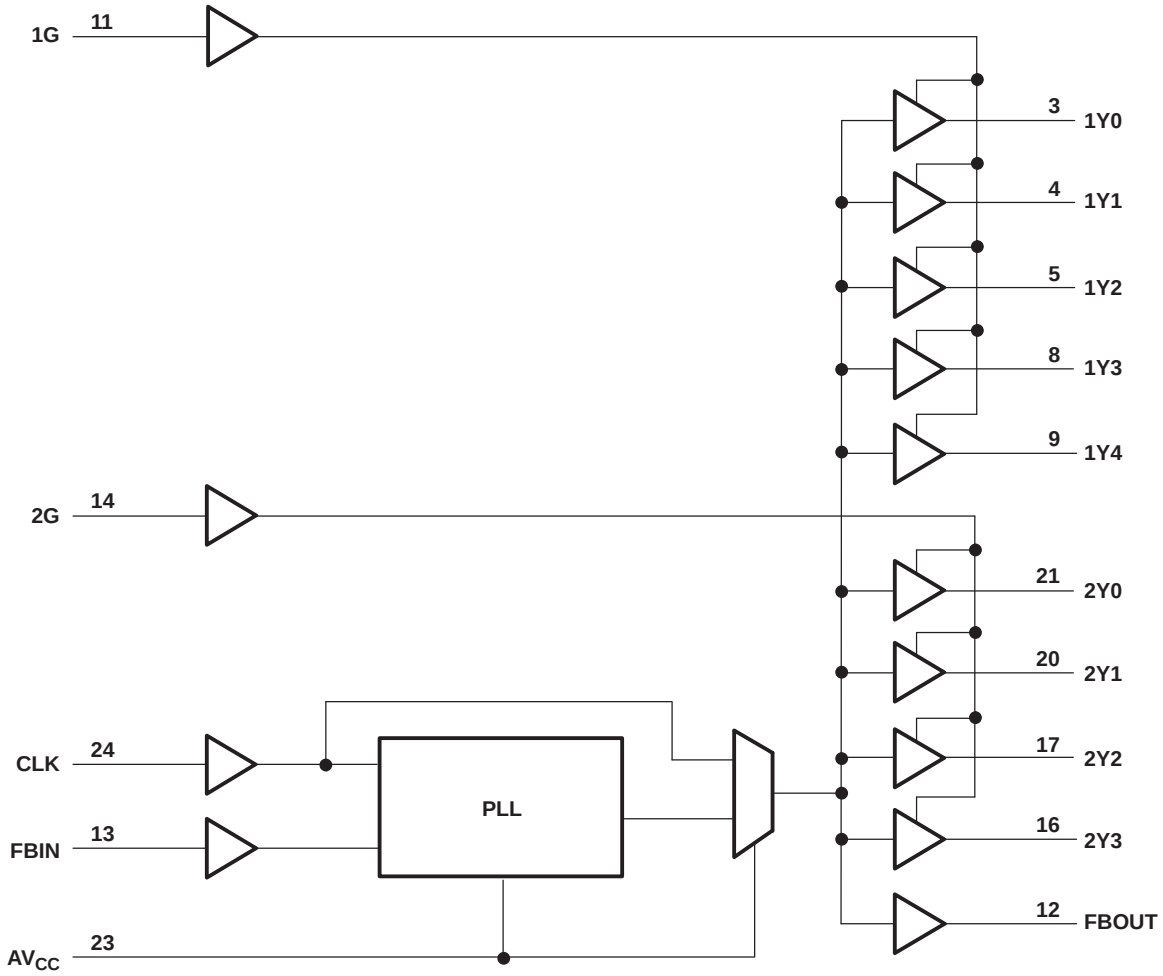
The CDCVF2509A is characterized for operation from 0°C to 85°C.

Because it is based on PLL circuitry, the CDCVF2509A requires a stabilization time to achieve phase lock of the feedback signal to the reference signal. This stabilization time is required following power up and application of a fixed-frequency, fixed-phase signal at CLK, and following any changes to the PLL reference or feedback signals. The PLL can be bypassed by strapping AV_{CC} to ground to use as a simple clock buffer.

FUNCTION TABLE

Inputs			Outputs		PLL
AVCC	**1G/2G**	**CLK**	**1Y/2Y**	**FBOUT**	
GND	L	Signal	L	Signal (delayed)	Bypassed / Off
GND	H	Signal	Signal (delayed)	Signal (delayed)	Bypassed / Off
3.3 V (nom)	L	CLK > 1 MHz	L	CLK (in phase)	On
3.3 V (nom)	H	CLK > 1 MHz	CLK (in phase)	CLK (in phase)	On
3.3 V (nom)	X	CLK < 1 MHz	L	L	Off

FUNCTIONAL BLOCK DIAGRAM



AVAILABLE OPTIONS

T_A	PACKAGE
	SMALL OUTLINE (PW)
0°C to 85°C	CDCVF2509APWR
	CDCVF2509APW

PACKAGE THERMAL RESISTANCE(1)

CDCVF2509APW 24-PIN TSSOP			THERMAL AIRFLOW (CFM)				UNIT
			0	150	250	500	
$R_{\theta JA}$	High K		88	83	81	77	°C/W
$R_{\theta JC}$	High K	26.5					

(1) The package thermal impedance is calculated in accordance with JESD 51 and JEDEC2S2P (high-k board).

Pin Functions

PIN NAME	PIN NO.	TYPE	DESCRIPTION
CLK	24	I	Clock input. CLK provides the clock signal to be distributed by the CDCVF2509A clock driver. CLK is used to provide the reference signal to the integrated PLL that generates the clock output signals. CLK must have a fixed frequency and fixed phase for the PLL to obtain phase lock. Once the circuit is powered up and a valid CLK signal is applied, a stabilization time is required for the PLL to phase lock the feedback signal to its reference signal.
FBIN	13	I	Feedback input. FBIN provides the feedback signal to the internal PLL. FBIN must be hard-wired to FBOUT to complete the PLL. The integrated PLL synchronizes CLK and FBIN so that there is nominally zero phase error between CLK and FBIN.
1G	11	I	Output bank enable. 1G is the output enable for outputs 1Y(0:4). When 1G is low, outputs 1Y(0:4) are disabled to a logic-low state. When 1G is high, all outputs 1Y(0:4) are enabled and switch at the same frequency as CLK.
2G	14	I	Output bank enable. 2G is the output enable for outputs 2Y(0:3). When 2G is low, outputs 2Y(0:3) are disabled to a logic low state. When 2G is high, all outputs 2Y(0:3) are enabled and switch at the same frequency as CLK.
FBOUT	12	O	Feedback output. FBOUT is dedicated for external feedback. It switches at the same frequency as CLK. When externally wired to FBIN, FBOUT completes the feedback loop of the PLL. FBOUT has an integrated 25-Ω series-damping resistor.
1Y (0:4)	3, 4, 5, 8, 9	O	Clock outputs. These outputs provide low-skew copies of CLK. Output bank 1Y(0:4) is enabled via the 1G input. These outputs can be disabled to a logic-low state by deasserting the 1G control input. Each output has an integrated 25-Ω series-damping resistor.
2Y (0:3)	16, 17, 21, 20	O	Clock outputs. These outputs provide low-skew copies of CLK. Output bank 2Y(0:3) is enabled via the 2G input. These outputs can be disabled to a logic-low state by deasserting the 2G control input. Each output has an integrated 25-Ω series-damping resistor.
AV_{CC}	23	Power	Analog power supply. AV_{CC} provides the power reference for the analog circuitry. In addition, AV_{CC} can be used to bypass the PLL. When AV_{CC} is strapped to ground, PLL is bypassed and CLK is buffered directly to the device outputs.
AGND	1	Ground	Analog ground. AGND provides the ground reference for the analog circuitry.
V_{CC}	2, 10, 15, 22	Power	Power supply
GND	6, 7, 18, 19	Ground	Ground

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted)(1)

		UNIT
AV_{CC}	Supply voltage range (2)	$AV_{CC} < V_{CC}$ +0.7 V
V_{CC}	Supply voltage range	–0.5 V to 4.3 V
V_I	Input voltage range (3)	–0.5 V to 4.6 V
V_O	Voltage range applied to any output in the high or low state(3) (4)	–0.5 V to V_{CC} + 0.5 V
I_{IK}	Input clamp current (V_I< 0)	–50 mA
I_{OK}	Output clamp current (V_O< 0 or $V_O > V_{CC}$)	±50 mA
I_O	Continuous output current (V_O = 0 to V_{CC})	±50 mA
	Continuous current through each V_{CC} or GND	±100 mA
	Maximum power dissipation at T_A = 55°C (in still air)(5)	0.7 W
T_{stg}	Storage temperature range	–65°C to 150°C

(1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
(2) AV_{CC} **must not** exceed V_{CC}+ 0.7 V
(3) The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
(4) This value is limited to 4.6 V maximum.
(5) The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, see the *Package Thermal Considerations* application note in the *ABT Advanced BiCMOS Technology Data Book* (SCBD002).

RECOMMENDED OPERATING CONDITIONS(1)

		MIN	MAX	UNIT
V_{CC}, AV_{CC}	Supply voltage	3	3.6	V
V_{IH}	High-level input voltage	2		V
V_{IL}	Low-level input voltage		0.8	V
V_I	Input voltage	0	V_{CC}	V
I_{OH}	High-level output current		–12	mA
I_{OL}	Low-level output current		12	mA
T_A	Operating free-air temperature	0	85	°C

(1) Unused inputs must be held high or low to prevent them from floating.

TIMING REQUIREMENTS

over recommended ranges of supply voltage and operating free-air temperature

		MIN	MAX	UNIT
f_{clk}	Clock frequency	20	175	MHz
	Input clock duty cycle	40%	60%	
	Stabilization time(1)		1	ms

(1) The time required for the integrated PLL circuit to obtain phase lock of its feedback signal to its reference signal. For phase lock to be obtained, a fixed-frequency, fixed-phase reference signal must be present at CLK. Until phase lock is obtained, the specifications for propagation delay, skew and jitter parameters given in the *switching characteristics* table are not applicable. This parameter does not apply for input modulation under SSC application.

ELECTRICAL CHARACTERISTICS

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V_{CC}, AV_{CC}	MIN	TYP(1)	MAX	UNIT
V_{IK}	Input clamp voltage	I_I = -18 mA	3 V			–1.2	V
V_{OH}	High-level output voltage	I_{OH} = -100 µA	MIN to MAX	V_{CC}–0.2			V
		I_{OH} = -12 mA	3 V	2.1			
		I_{OH} = -6 mA	3 V	2.4			
V_{OL}	Low-level output voltage	I_{OL} = 100 µA	MIN to MAX			0.2	V
		I_{OL} = 12 mA	3 V			0.8	
		I_{OL} = 6 mA	3 V			0.55	
I_{OH}	High-level output current	V_O= 1 V	3 V	–28			mA
		V_O = 1.65 V	3.3 V		–36		
		V_O = 3.135 V	3.6 V			-8	
I_{OL}	Low-level output current	V_O= 1.95 V	3 V	30			mA
		V_O = 1.65 V	3.3 V		40		
		V_O = 0.4 V	3.6 V			10	
I_I	Input current	V_I = V_{CC} or GND	3.6 V			±5	µA
I_{CC} (2)	Supply current (static, output not switching)	V_I = V_{CC} or GND, I_O = 0, Outputs: low or high	3.6 V, 0 V			40	µA
ΔI_{CC}	Change in supply current	One input at V_{CC} - 0.6 V, Other inputs at V_{CC} or GND	3.3 V to 3.6 V			500	µA
C_i	Input capacitance	V_I = V_{CC} or GND	3.3 V		2.5		pF
C_o	Output capacitance	V_O = V_{CC} or GND	3.3 V		2.8		pF

(1) For conditions shown as MIN or MAX, use the appropriate value specified under the *recommended operating conditions* section.
(2) For dynamic I_{CC} vs Frequency, see Figure 9 and Figure 10.

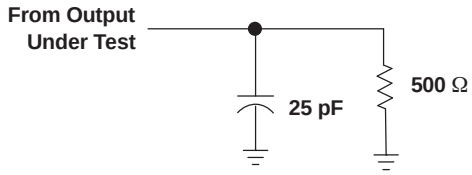
SWITCHING CHARACTERISTICS

over recommended ranges of supply voltage and operating free-air temperature, C_L = 25 pF (see Figure 1 and Figure 2)(1) (2)

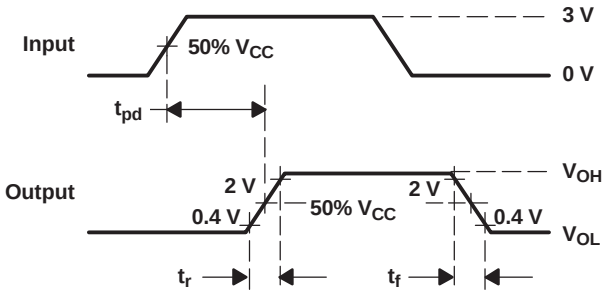
PARAMETER		FROM (INPUT)	TO (OUTPUT)	V_{CC}, AV_{CC} = 3.3 V ± 0.3 V			UNIT
				MIN	TYP	MAX	
$t_{(\phi)}$	Phase error time- static (normalized) (see Figure 4 through Figure 7)	CLK↑ = 25 MHz to 65 MHz	FBIN↑	–150		150	ps
		CLK↑ = 66 MHz to 166 MHz		–125		125	
$t_{sk(o)}$	Output skew time(3)	Any Y	Any Y			100	ps
	Phase error time-jitter (4)	CLK = 66 MHz to 100 MHz	Any Y or FBOUT	–50		50	ps
	Jitter$_{(cycle-cycle)}$ (see Figure 8)	CLK = 25 MHz to 40 MHz	Any Y or FBOUT			500	ps
		CLK = 41 MHz to 59 MHz				200	
		CLK = 60 MHz to 175 MHz			65	125	
$t_{d(o)}$	Dynamic phase offset(5)	CLK↑ = 25 MHz to 65 MHz	FBIN↑			1.5	ns
		CLK↑ = 66 MHz to 166 MHz				0.4	
	Duty cycle	$f_{(CLK)}$ > 60 MHz	Any Y or FBOUT	45%		55%	
t_r	Rise time	V_O = 0.4 V to 2 V	Any Y or FBOUT	0.3		1.1	ns/V
t_f	Fall time	V_O = 2 V to 0.4 V	Any Y or FBOUT	0.3		1.1	ns/V
t_{PLH}	Low-to-high propagation delay time, bypass mode	CLK	Any Y or FBOUT	1.8		3.9	ns
t_{PHL}	High-to-low propagation delay time, bypass mode	CLK	Any Y or FBOUT	1.8		3.9	ns

(1) The specifications for parameters in this table are applicable only after any appropriate stabilization time has elapsed.
(2) These parameters are not production tested.
(3) The $t_{sk(o)}$ specification is only valid for equal loading of all outputs.
(4) Calculated per PC DRAM SPEC ($t_{phase\ error}$, static-jitter$_{(cycle-to-cycle)}$).
(5) The parameter is assured by design but cannot be 100% production tested.

PARAMETER MEASUREMENT INFORMATION



LOAD CIRCUIT FOR OUTPUTS



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES

NOTES: A. C_L includes probe and jig capacitance.
B. All input pulses are supplied by generators having the following characteristics: PRR ≤ 133 MHz, Z_O = 50 Ω, t_r ≤ 1.2 ns, t_f ≤ 1.2 ns.
C. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION (continued)

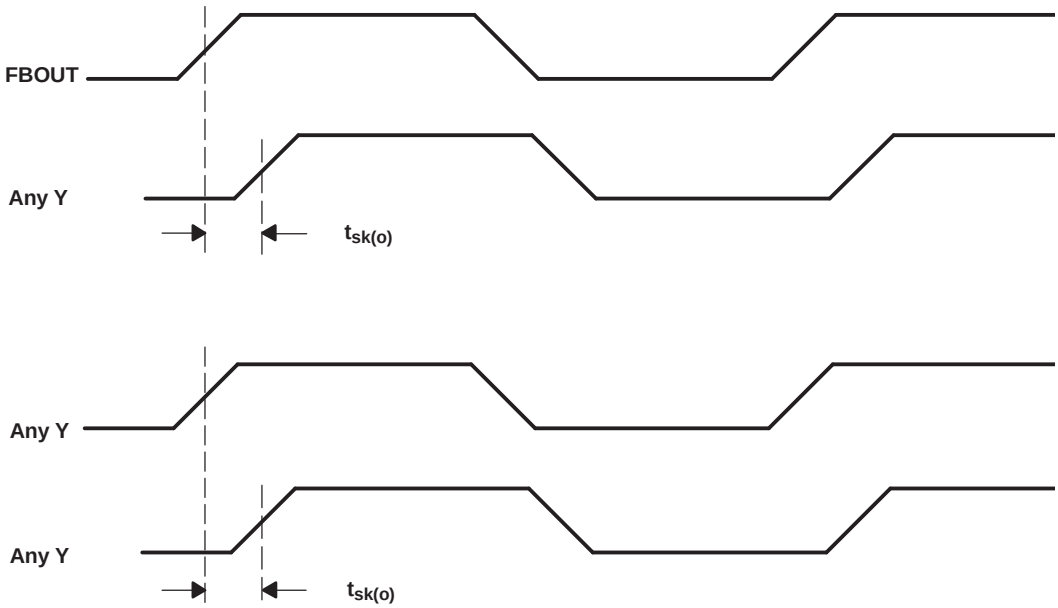
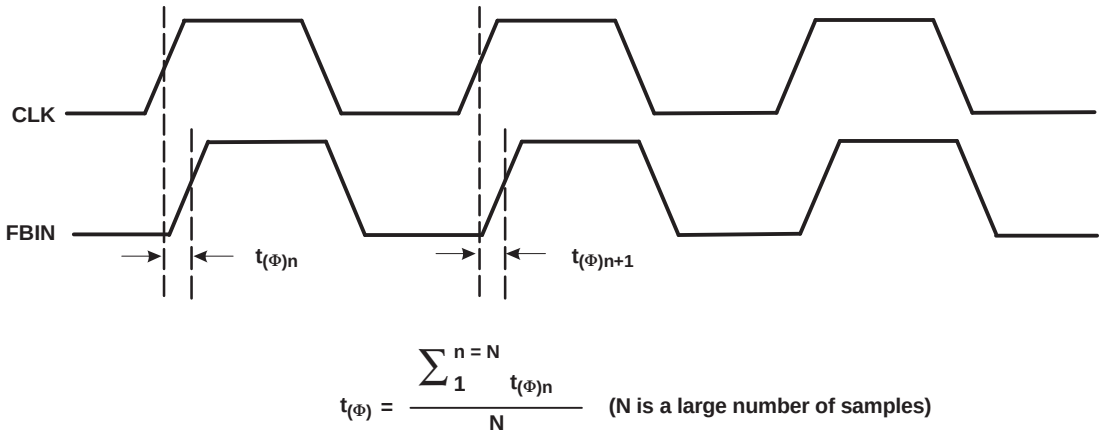


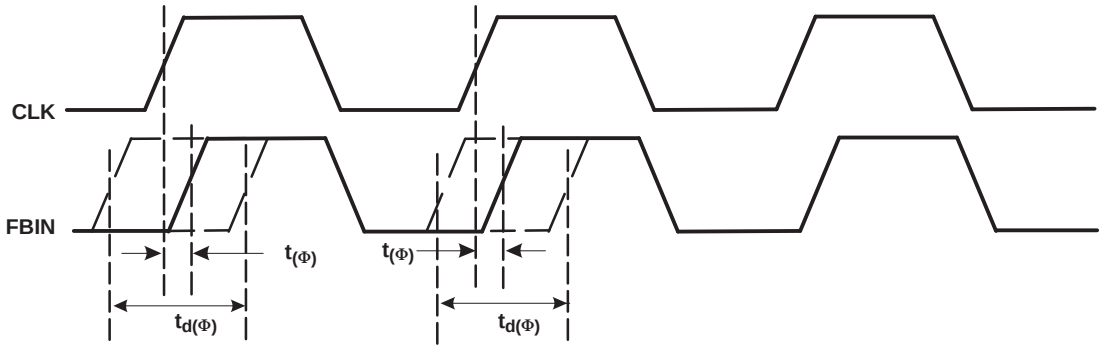
Figure 2. Skew Calculations

PARAMETER MEASUREMENT INFORMATION (continued)



$$t_{(\Phi)} = \frac{\sum_{1}^{n=N} t_{(\Phi)n}}{N}$$ (N is a large number of samples)

a) Static Phase Offset



b) Dynamic Phase Offset

Figure 3. Static and Dynmaic Phase Offset

TYPICAL CHARACTERISTICS

STATIC PHASE ERROR vs LOAD CAPACITANCE

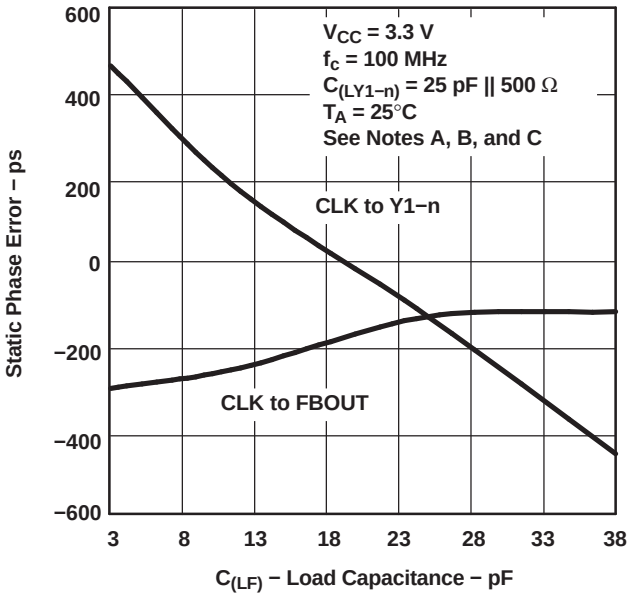


Figure 4.

STATIC PHASE ERROR vs LOAD CAPACITANCE

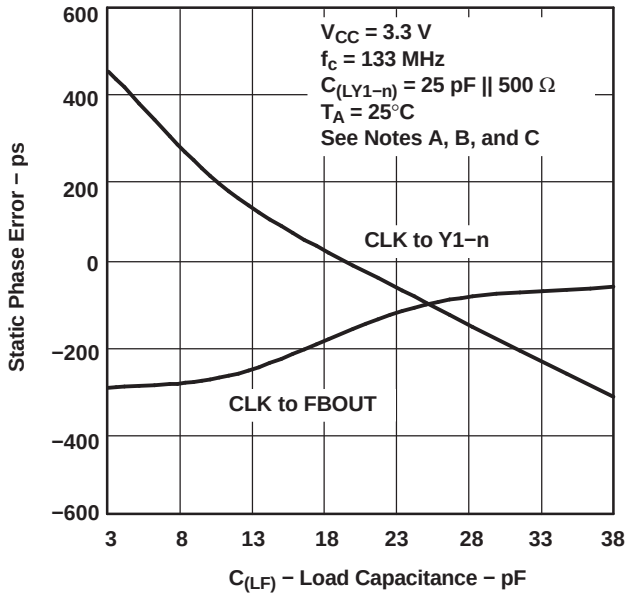


Figure 5.

STATIC PHASE ERROR vs SUPPLY VOLTAGE AT FBOUT

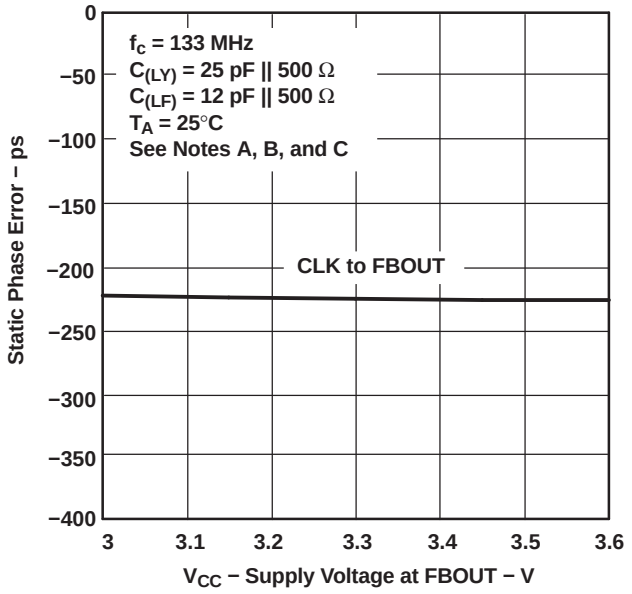


Figure 6.

STATIC PHASE ERROR vs CLOCK FREQUENCY

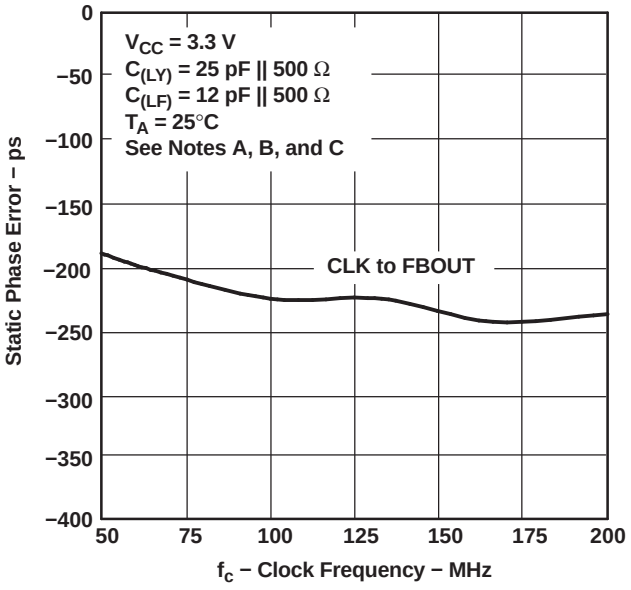


Figure 7.

a. Trace length FBOUT to FBIN = 5 mm, Z_O = 50Ω
b. $C_{(LY)}$ = Lumped capacitive load Y_{1-n}
c. $C_{(LFx)}$ = Lumped feedback capacitance at FBOUT = FBIN

TYPICAL CHARACTERISTICS (continued)

JITTER vs CLOCK FREQUENCY AT FBOUT

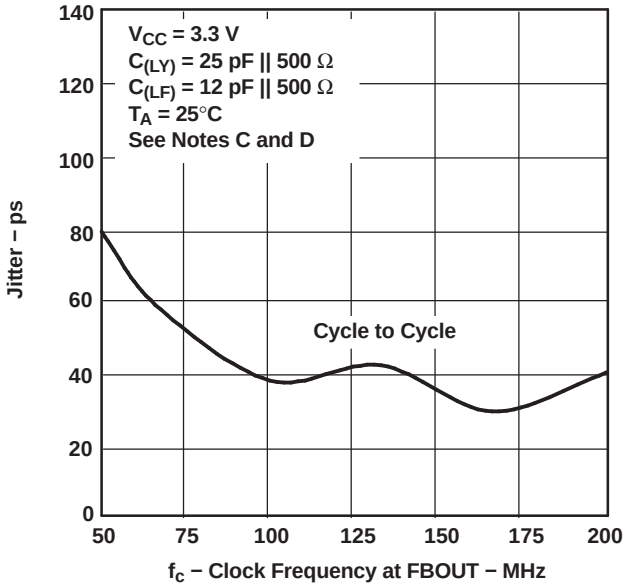


Figure 8.

ANALOG SUPPLY CURRENT vs CLOCK FREQUENCY

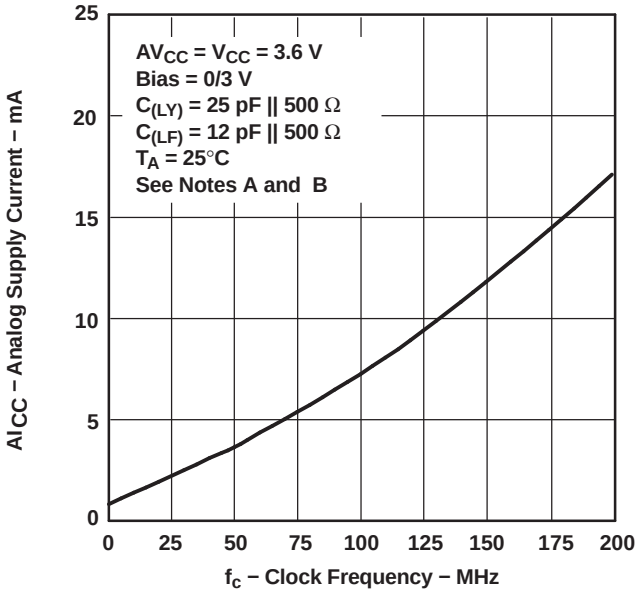


Figure 9.

SUPPLY CURRENT vs CLOCK FREQUENCY

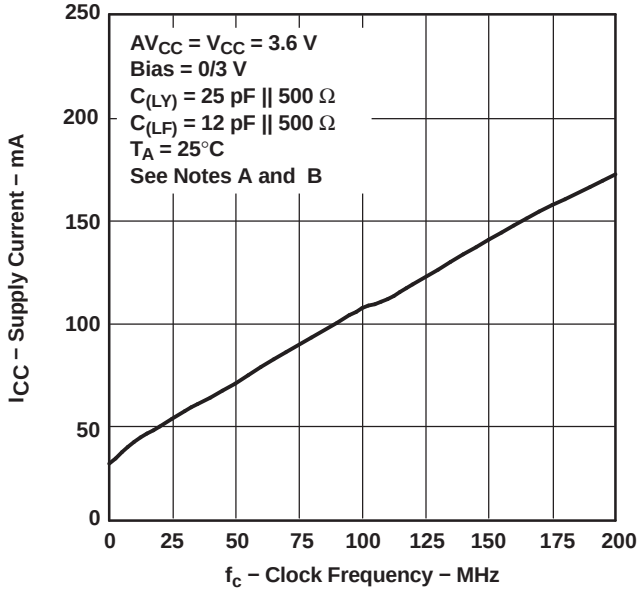


Figure 10.

a. Trace length FBOUT to FBIN = 5 mm, Z_O = 50 Ω
b. $C_{(LY)}$ = Lumped capacitive load Y_{1-n}
c. $C_{(LFx)}$ = Lumped feedback capacitance at FBOUT = FBIN
d. $C_{(LFx)}$ = Lumped feedback capacitance at FBOUT = FBIN.

REVISION HISTORY

Changes from Original (April 2004) to Revision A **Page**

- Changed the AVAILABLE OPTIONS table layout 3

Changes from Revision A (July 2004) to Revision B **Page**

- Changed Features bullet - From: Jitter (cyc - cyc) at 66 MHz to 166 MHz Is Typ = 70 ps To: Jitter (cyc - cyc) at 60 MHz to 175 MHz Is Typ = 65 ps 1
- Added Phase error time- static - CLK↑ = 25 MHz to 65 MHz - to the SWITCHING CHARACTERISTICS table 6
- Changed Jitter values in the SWITCHING CHARACTERISTICS table 6
- Added Dynamic phase offset to the SWITCHING CHARACTERISTICS table 6
- Changed Figure 2, Skew Calculations 7
- Added Figure 3, Static and Dynmaic Phase Offset 8

Changes from Revision B (June 2005) to Revision C **Page**

- Changed the FUNCTION TABLE - replaced with new table entries for clarity 2

Changes from Revision C (January 2009) to Revision D **Page**

- Changed the FUNCTION TABLE column 1 label From: AVDD To: AVCC 2
- Added the PACKAGE THERMAL RESISTANCE table 3

Changes from Revision D (February 2010) to Revision E **Page**

- Changed the FUNCTION TABLE CLK column for 3.3V (nom) L and H entries From: CLK < 1 MHz To: CLK > 1 MHz 2

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish	MSL Peak Temp (3)
CDCVF2509APW	ACTIVE	TSSOP	PW	24	60	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
CDCVF2509APWG4	ACTIVE	TSSOP	PW	24	60	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
CDCVF2509APWR	ACTIVE	TSSOP	PW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
CDCVF2509APWRG4	ACTIVE	TSSOP	PW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM

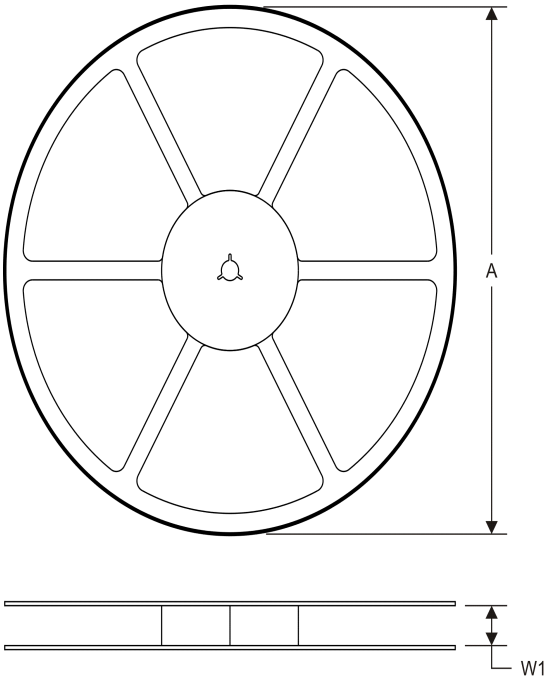
(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.
TBD: The Pb-Free/Green conversion plan has not been defined.
Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.
Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.
Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

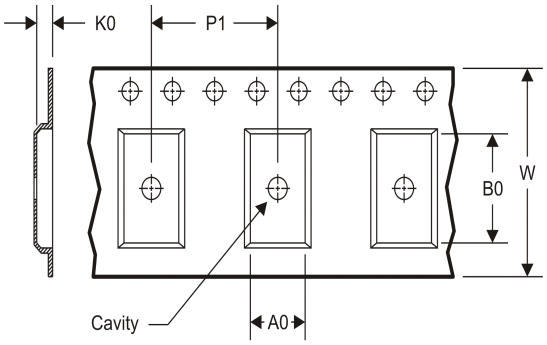
(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

TAPE AND REEL INFORMATION

REEL DIMENSIONS



TAPE DIMENSIONS



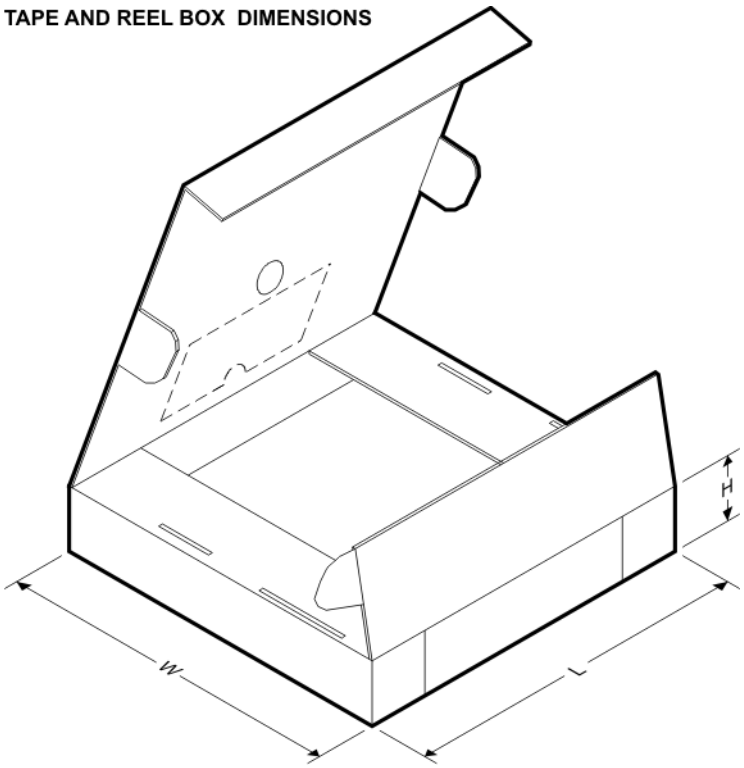
A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

TAPE AND REEL INFORMATION

*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CDCVF2509APWR	TSSOP	PW	24	2000	330.0	16.4	6.95	8.3	1.6	8.0	16.0	Q1

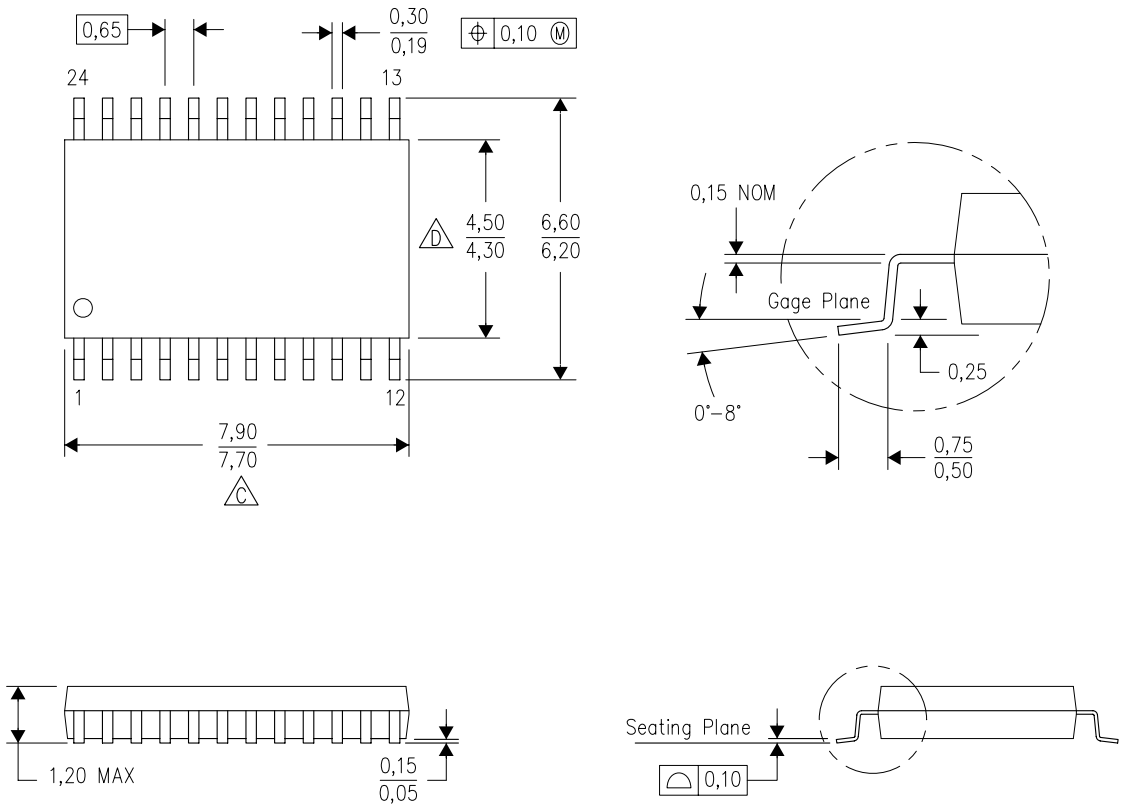
TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CDCVF2509APWR	TSSOP	PW	24	2000	367.0	367.0	38.0

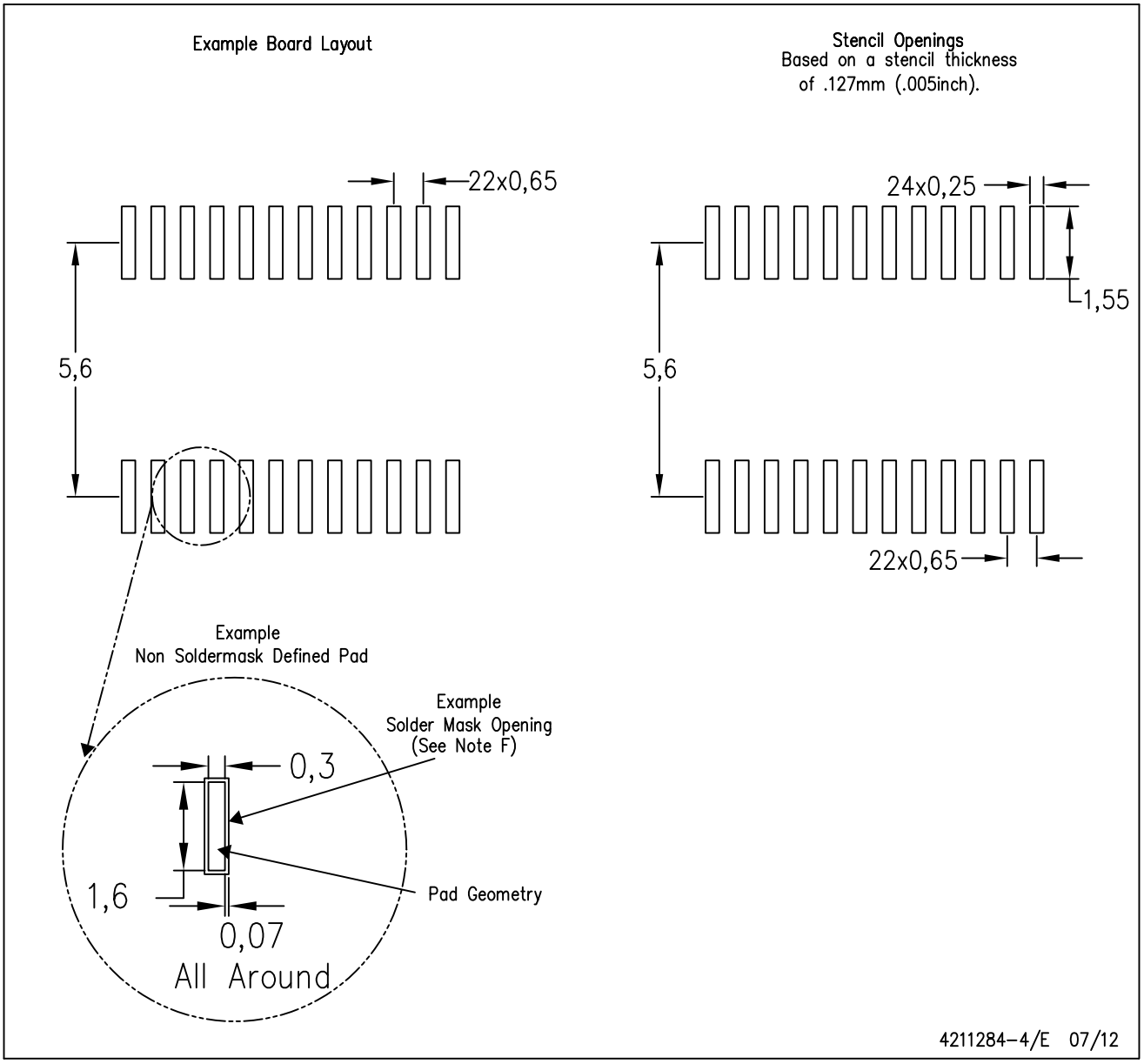
PW (R–PDSO–G24) PLASTIC SMALL OUTLINE



4040064–6/G 02/11

NOTES:
A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M–1994.
B. This drawing is subject to change without notice.
C. Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
D. Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
E. Falls within JEDEC MO–153

PW (R–PDSO–G24) PLASTIC SMALL OUTLINE



NOTES:
A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Publication IPC–7351 is recommended for alternate design.
D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC–7525 for other stencil recommendations.
E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.

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